

We make the invisible visible helping manufacturers, researchers, and educators get the most out of their materials

Our Trusted Partners







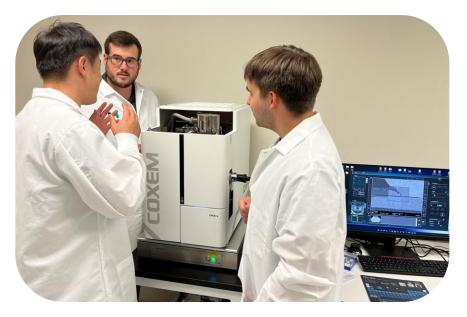












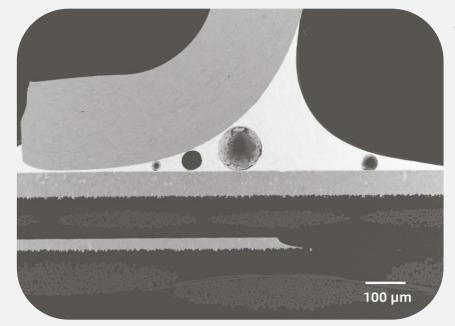
Services Offered:

- Failure Analysis ٠
- Materials • Characterization
- Sample Preparation
- Quality Validation



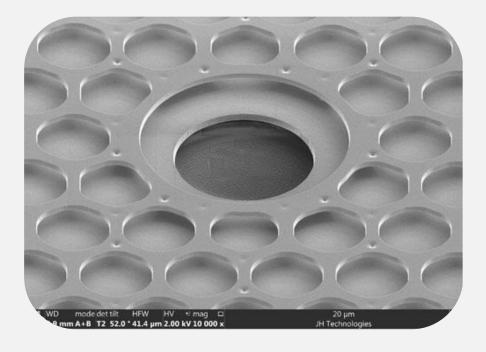






Complete Workflow Solutions

- Sectioning & Polishing
- Sample Prep for Electron • Microscopy
- Electron, Optical, & X-Ray Imaging /Analysis
- Metrology/Surface Profiling
- Hardness testing •
- Data Output





Lab Services

Applications

- **X** Microtechnology
- **V** Medical Devices
- Semiconductor
- K Metallography



Material Science

Sample Preparation for Electron Microscopy

Featured Equipment:

- Metrology •
- Metallography • Sample Prep
- EM Sample Prep
- SEM 's
- Hardness Tester's •
- Imaging /Analysis

Four Demonstration Centers and Our Analytical Lab

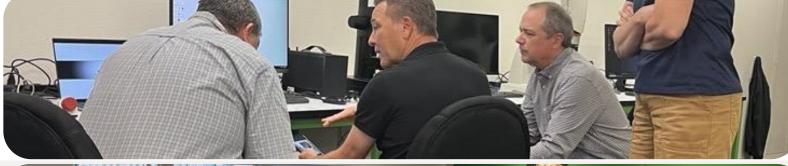


Fremont, CA Showroom & Analytical Lab

- Applications
- engineers
- Imaging support
- Analytical services











Company Headquarters

- Over 100 years of combined experience
- \$2 million of demo inventory

• Stocking warehouse

Southern California Showroom

18025 Sky Park Circle, Suite M Irvine, CA 92614

Pacific Northwest Showroom

7969 SW Cirrus Dr. Bldg 22 Beaverton, OR 97007

New England Showroom

11 Trafalgar Sq. Ste 103 Nashua, NH 03063

Main TOC

Community Service Program

iFuSE – Inspiring Future Scientific Exploration



Help educate our future generation.

Donate or trade-in your old microscopes to us and we will refurbish and donate them to K-12 schools with active STEM programs

Giving Teachers The Tools To Illuminate Young Minds

Some of the schools we have donated to:

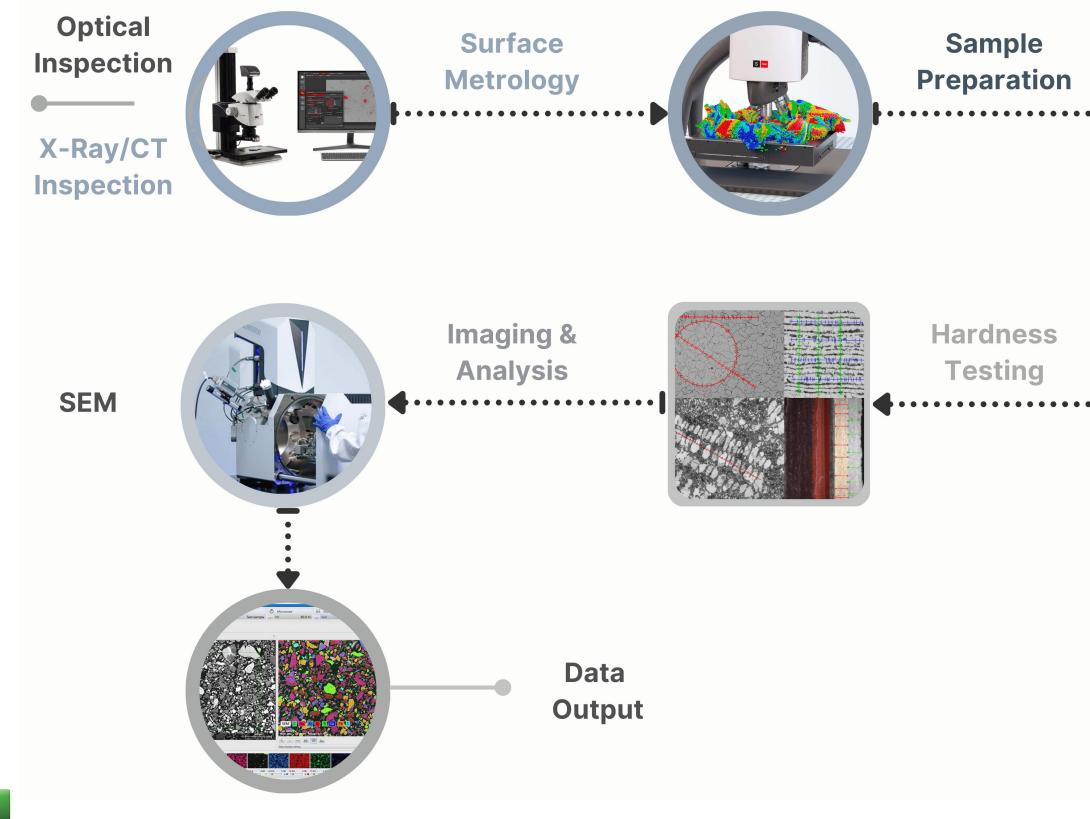
- Blair School, Kenya
- Synapse School, CA
- Liberty High School, CA
- And many more...<u>www.iFuSE.us</u>





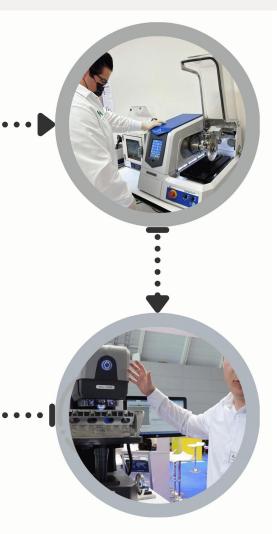
Donating To K-12 Schools

Failure Analysis Workflow



JH TECHNOLOGIES"

Workflow Solutions



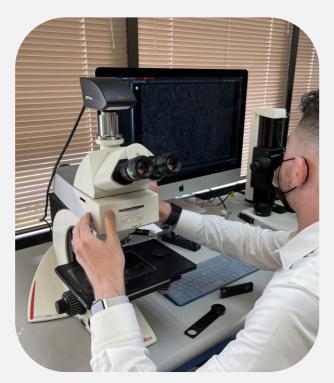
Warranty and Maintenance Services



Preventative Maintenance

Regular inspections, calibrations, and tune-ups help extend the lifespan of your instruments, minimize downtime, and ensure optimal imaging quality.





Extended Warranty

We offer extended warranties on most brands, providing:

- Longer coverage for peace of mind.
- Expert repairs using certified parts.
- Minimized downtime with priority service.
- Optimized performance through regular maintenance.





Products We Service & Repair

Buehler, Bruker, Ciqtek, COXEM, Leica, Navitar, Oxford, Olympus, Nikon, Semprex, Sensofar, Xavis

Call for other manufacturers

User Training/Process Development:

- Microscope Hardware & Software
- SEM Hardware & Software
- X-Ray Hardware & Software
- Sample Preparation
- Process Development

Products

Table of Contents







JH TECHNOLOGIES™

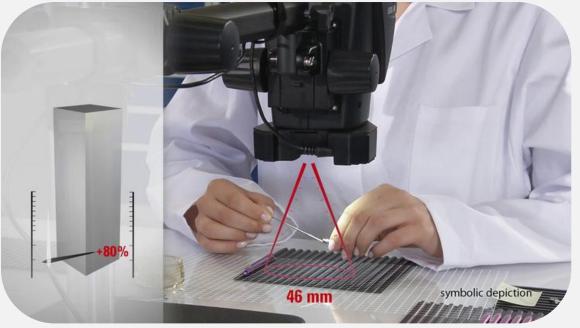
Microscopes

Education Microscopes

Microscope Lighting

Routine Stereo Microscopes For Inspection & Rework

A Series

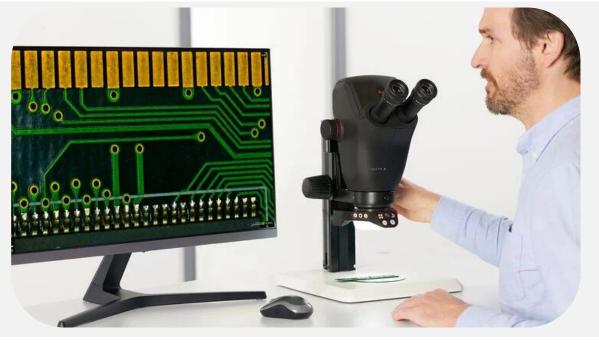


Increase your efficiency

For fast, comfortable and convenient work in production, assembly and rework.

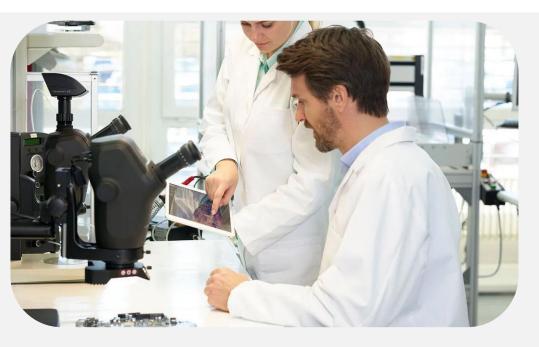


Ivesta 3 Series



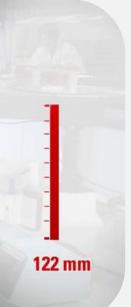
Results you can rely on

Ensure consistent visual inspection according to standard procedures reducing the risk of human errors.





Stereo Microscopes



Flexibility & Large Area Inspection

The table clamp allows maximum freedom of movement while requiring minimum table space. Ideal for handling large samples.

Facilitate inspection and measurement

Reproduce zoom settings through click-stops. Magnification settings are automatically saved along with the image data, using encoded zoom.



Routine Stereo Ergonomic Microscopes

M 50/60/80/125 Series



Accuracy for repetitive tasks

Create traceable measurement procedures for repetitive jobs using the predefined zoom steps of the M50 or the click stops of the M60, M80. or M125





Working efficiently with Ergo accessories

Increase your productivity with an entirely ergonomic microscope for maximum comfort





Stereo Microscopes

High flexibility with a modular concept

Customize the microscope to suit your needs with a large range of ergonomic accessories and illumination options

Customizable for any application

Whether your work requires a variety of illumination techniques, different objectives, or a larger stand, let us help you choose the best solution for your application





Research/Material Analysis Grade

M 165/205 Series



Tailored solutions – for those who demand more

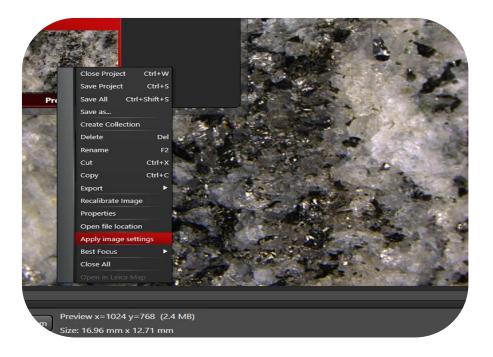
Automated solutions designed to increase thruput with motorized stages, focus, and reproducible illumination





Easily acquire calibrated images

For accurate results and consistent documentation





Stereo Microscopes

High flexibility with a modular concept

Customize the microscope to suit your needs with a large range of ergonomic accessories and illumination options

Easily recall settings at any time

Fully encoded systems for repeatability
Simple, easy to use software to setup automated processes



Fluorescence Stereo Microscopes

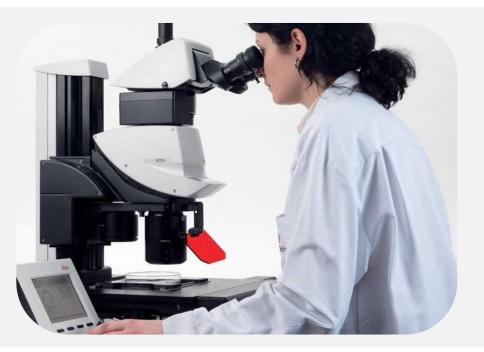
• Research M 165/205 Series



• Routine M80, Ivesta Series

Discover the automated world of research

- Leica M205 FA: fully motorized fluorescence stereo microscope
- Revolutionizes fluorescence
 microscopy research
- Advanced automation capabilities





Finest details in 3D

- FusionOptics technology overcomes optical limitations
- Combines high resolution with excellent depth of field (DOF)
- Delivers superior image brightness for better 3D orientation





Stereo Microscopes

Bright fluorescence signals

- Separated yet synchronized beam paths
- Dedicated paths: one for excitation light, two for observation
- Evenly illuminated field of view at any zoom position

Fluorescence Routine Instrument

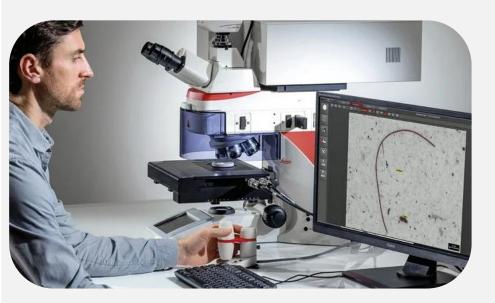
- LED light sources for basic instruments and routine applications
- Wide variety of configurations and wavelengths available
- Cost-effective solution for standard fluorescence needs





Upright Compound Microscopes

Cleanliness, Materials Science, Semiconductors



Cleanliness Analysis of Components

- Get particle composition and structure data simultaneously
- Make confident decisions faster during analysis





JH TECHNOLOGIES

Semiconductor Inspection Systems

Visualize Structures and Defects

- Detect, analyze, and measure scratches, contamination, and various features
- Choose from multiple illumination options: brightfield, darkfield, polarization, DIC, fluorescence, and infrared
- Enhance resolution with ultraviolet light

Compound Microscopes

Upright microscopes for industrial and materials

- Inspect and document results efficiently
- Customizable with LED illumination and ergonomic accessories

Quick Defect Detection

 Reveal macro defects using optional 0.7x Macro objective • 36mm field of view enables fast orientation and efficient screening • Save time with rapid sample assessment





Inverted Compound Microscopes



High-performance optics

- Superior image resolution and • contrast using incident light, brightfield, polarization, and fluorescence
- Handles large samples efficiently
- Saves time during serial inspection and high-volume testing



Six contrast methods in one system



Large Working Distance

- Two-condensers option with flexible working distances: •
 - s40/0.45 condenser: 40-50 mm working distance with 10 mm free space adjustment
 - s80/0.30 condenser: 80 mm working distance with simple installation
- No need to remove illumination arm when changing condensers ٠



Compound Microscopes

• Switch between samples 4× faster • Accommodate samples weighing up to 30 kg • Utilize UC-3D Illumination technology • Achieve top resolution from any angle for more accurate inspection results



Forensic Microscopes



Comparison Microscopes

- Detect and identify the slightest differences in forensic evidence
- Examine bullets, cartridge cases, tool marks, and documents with precision
- Ensure accurate, reproducible results for reliable conclusions





Forensic Medicine

- Supports multidisciplinary applications: biology, pathology, anthropology, toxicology, and DNA analysis
- Features tailored microscopes, cameras, and software for effective lab work
- Offers versatile optics, illumination options, and specialized forensic software •



Compound Microscopes

Flexibility with precision and reliability

- Adaptable with specialized object mountings:
 - Rotary stages
 - Large object stages
 - Tilting stages
 - Bullet holders
 - Various custom mounts
- Designed for versatility without ٠ compromising accuracy

Sub TOC

Main TOC



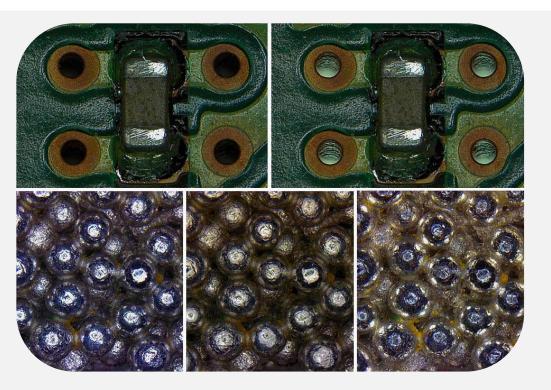
DVM6 Digital Versatile Microscope



Explore in a flexible way

- Ideal solution for failure-analysis and R&D applications
- Single versatile platform for multiple research need





Reveal more details by combining options for illumination and contrasting in various ways.

- Ring light illumination (RL): View textured surfaces using one or all four segments
- Coaxial illumination (CXI): Visualize flat, reflective samples
- Transmitted light illumination (BLI): Explore holes and transparent materials
- Reduce glare on reflective samples with diffuser adapter or polarizer



Digital Microscopes

Investigate your samples with ease

- Versatile digital microscope for comprehensive sample investigations
- Features convenient operation to maintain focus on work
- Ensures reliable results with reproducible imaging conditions

one or all four segments s ansparent materials or polarizer



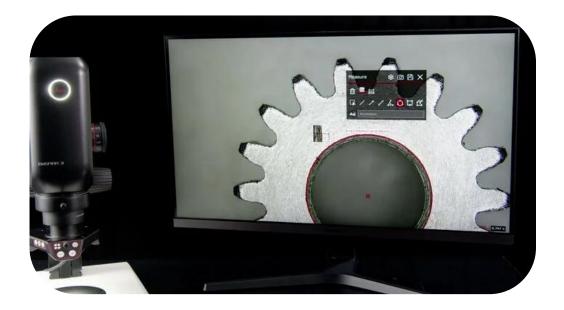


EMSPIRA 3 Digital Microscope



Streamline your inspection process

The advantage of optimized inspection and adaptability to your needs combined in a single system.





Get easy access to images

Create high contrast images and videos, reducing training and supervision time.





Digital Microscopes

A flexible solution you can rely on

Flexibility to inspect and document according to your needs, access your data when you need it and work in industrial environments.

Measure and annotate directly without a PC

In stand-alone mode, you can measure multiple regions on the sample in the live image and save the results with it.



Digital Classroom



Compound Microscopes

- Precision optics with modern technology
- Integrated wireless camera for seamless documentation and viewing
- Exceptional clarity and ease of use
- Ideal for educational and routine laboratory applications





Wireless Classroom

- Digital Imaging Technology increases learning time and student engagement
- Interactive learning solutions include microscopes, cameras, and software
- Comprehensive ecosystem to enhance educational outcomes



Education Microscopes

Dissecting Microscopes

A key instrument for your laboratory or classroom

- Essential instrument for laboratory or classroom settings
- Proper selection ensures longlasting, satisfactory use
- Designed for extended dissection sessions by students and researchers

increases ngagement s include oftware o enhance



Biology | Geology | Material Science



Educational stereo microscopes

The integrated 5-megapixel cameras can live-stream HD images to students' smartphones or tablets.





Camera access for multiple students simultaneously

Connect multiple smartphones or tablets and quickly access highresolution images or videos fast directly onto your device through the camera's Wi-Fi stream.





Dissecting Microscopes

EZStore[™] design

EZStore[™] design with Handle and Cord Wrap allows easy carrying, easy lifting and easy cord storage

Greenough Stereo Microscopes

You can optimize your visual inspection and rework while achieving reliable, consistent results with stereo microscopes.





Biology | Geology | Material Science



Student-friendly

Supports a Student Friendly Classroom Environment -Binocular, fluorescence-capable educational microscope for life science courses





The EZLite[™] LED Illumination

One of the teacher-friendly features, provides cool white light with a life-time of over 20 years average use.





Compound Microscopes

AgTreat™

All touchpoints treated to prevent bacteria spreading from student to student

Inverted microscope supports your specific work routine

The DMil camera version is an allin-one solution for image capturing and cell culture documentation. The 12 mp camera transforms your microscope into a stand-alone digital imaging station with no need for a PC





Compound Microscopes



Cameras

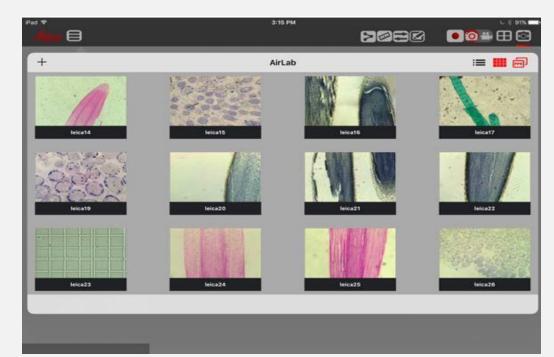
These 5-megapixel cameras can live-stream HD images to students' smartphones or tablets. Students can connect either through its own internal Wi-Fi signal or through the facilities network.





Interactive Classroom with Airlab

Work with live image thumbnail overviews of all connected microscopes, share up to four images in class.





Digital Classroom

Leica AirLab App for easy learning and sharing

Capture, measure, annotate and archive microscope images with a mobile device.

Live thumbnail overview AirLab

Overview all connected microscopes in class with a full-screen thumbnail overview.







Compound Microscopes



Ring Lights

- Durability (25,000 to 50,000 hours, depending on the model)
- A natural color temperature
- Low power consumption (compared to halogen lamps)
- The illuminator can have a very compact design
- Usually operated without a fan (no noise)





Diffuse/Polarized

Light characteristic 36 high-output LEDs produce bright, uniform light.





Microscope Lighting

Incident Lights

Bright incident contrast

Integrated 4-point LED top light – ensures a homogeneous and bright incident illumination.

UV/Fluorescent

High-performance fluorescence with differential interference contrast, phase, and polarization contrast.









Diffuse Ring Light

Spotlight illuminators are very useful for all kind of applications, where different contrast for reflected light is important.





Incident Light

With its flexible two-armed gooseneck and integrated LED spotlights, makes it easier for you to adjust the contrast for incident light.





Microscope Lighting



Backlight

You benefit from bright, crisp images with distinct margins, injected directly into the microscope eyepieces.

Diffuse Dome Light

Produces a uniform light by means of the dome shape. The mechanically flexible design with silicone rubber eases your access to the specimen.





UV/Blue Light

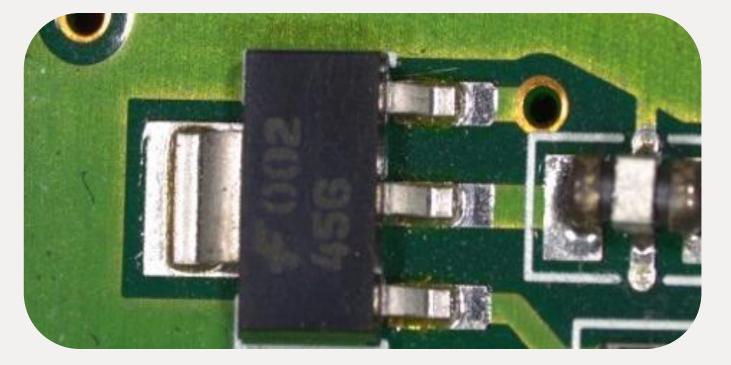


7- way LED illumination

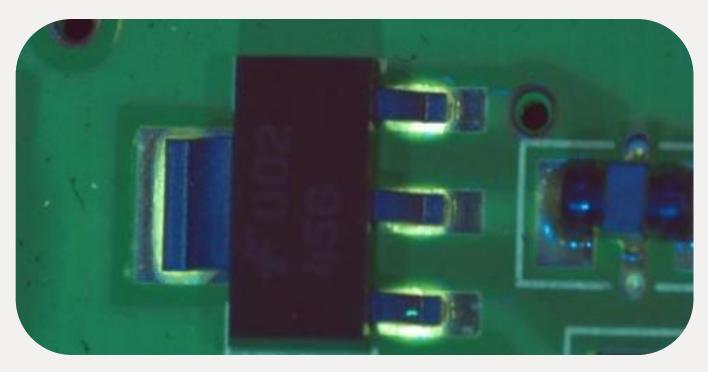
Provides incident, oblique and transmitted light for high quality illumination and contrast of any application.







Standard Bright Field White Light LED





Microscope Lighting

Stereo Microscope Fluorescence Adapter

Allows you to easily add powerful fluorescent illumination to your Leica EZ4 or S9 Series Microscope

Blue Light Fluorescence Highlighting Epoxy







Metallographic sample preparation and analysis instruments







Metallography Equipment

METALLOGRAPHY SUPPLIES & CONSUMABLES

> MATERIAL ANALYSIS & METALLOGRAPHY SOFTWARE

> > Main TOC



Gravity-fed Precision Sectioning Machine

IsoMet Low Speed

Manual Sectioning



IsoMet High Speed Automatic Precision Sectioning



IsoMet 1000 Low Speed Sectioning



AbrasiMet M Manual Abrasive Sectioning





Sectioning

PetroThin Petrographic Sectioning



AbrasiMet L Automatic Abrasive Sectioning





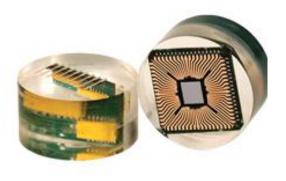




Compression Mounting Compounds



Acrylic Systems



Epoxy Systems



Release Agent



Mounting Accessories



PetroBond





Mounting



Simplivac Cold Vacuum Mounting



SimpliMet 4000 Hot Vacuum Mounting





EcoMet 30 Semi-Auto

The user-friendly touchscreen interface puts all regularly used functions on the simple front screen menus reducing process time.





VibroMet

Prepares high-quality polished surfaces on a wide variety of materials. Supports sample preparation for EBSD Analysis





Grinding & Polishing

IsoMet 30 Twin

All EcoMet/AutoMets have durable construction for reliability in high use environments, unique quick cleaning features, and plenty of enhancements for user-friendly operation.

AutoMet 250/300

Designed for manual or automated sample preparation. Simplicity is balanced with versatility to accommodate many applications and larger areas.

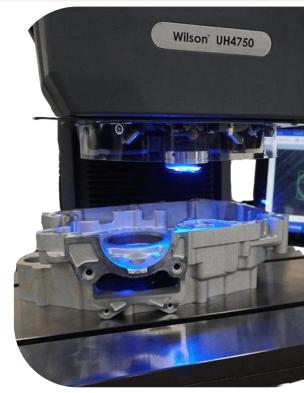


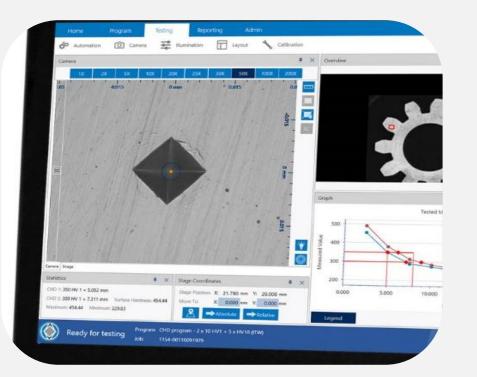




Vickers

- Vickers
- Vickers-Knoop
- Macro Vickers





Accessories

- Diamet Testing Software
 - Offering varying levels of automation, comprehensive DiaMet software is a user-friendly system providing automatic test and measurement indentations, programmed testing sequences, and report generation.
- Test Blocks



Hardness Testing



Rockwell, Brinell, Universal

- Wilson Universal
- Wilson Rockwell •
- Wilson Brinell





Wilson Vickers & Knoop VH3300

- Fast and simple operation for inexperienced operators
- Maintains flexibility and advanced features for expert users
- Features DiaMet operation software for comprehensive testing





Wilson Micro Hardness VH1102 & 1202

- Versatile systems supporting both Knoop and Vickers testing methods
- Affordable and reliable solution for precise micro-hardness testing
- Suitable for quality control and metallurgical research applications



Hardness Testing

Wilson Vickers & Knoop VH3100

- Collision Resistant System prevents indenter and objective damage
- Fully integrated system with components and software designed by Buehler
- Complete hardness testing solution in one package









Wilson Universal Hardness Tester UH4000

Can perform several different hardness scales in one machine including Vickers, Knoop, Brinell and Rockwell, in most cases at higher loads



Wilson Rockwell 2000 Hardness Tester

Achieve the highest level of depth measurement accuracy and resolution available and as a result has the best GR&R performance in the industry.

This machine is offered in two sizes ranging from 10 - 14 in of vertical testing capacity to accommodate varying sample sizes and is available in three different variations of Rockwell Regular, Superficial, or Twin hardness scales.



Wilson Brinell Hardness Tester BH3000

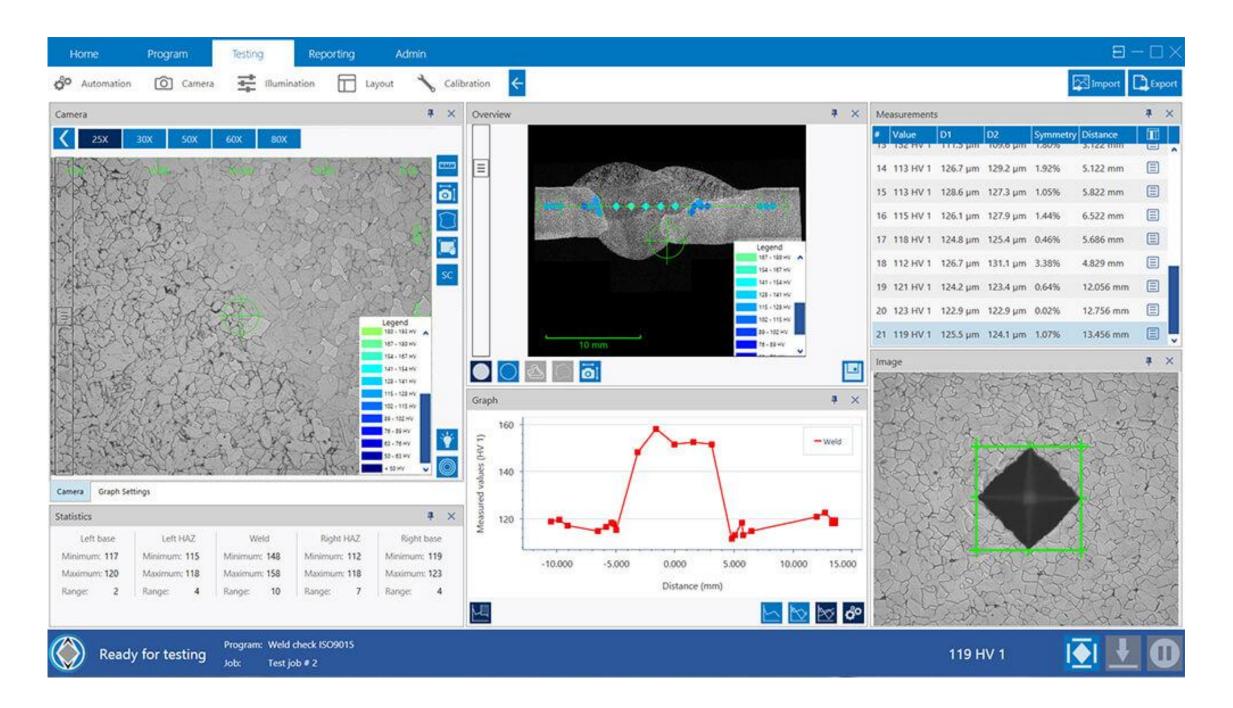
Designed with rugged construction to withstand harsh environments, the reliable BH3000 Brinell hardness testing machine combines high rigidity and closed-loop load cell technology to ensure accurate and safe load applications.



Hardness Testing









Hardness Testing

Diamet Hardness Testing



DiaMet hardness testing software breaks from the usual approach by offering a fast and simple way to perform hardness tests. This makes it easy for less experienced operators to use, while still providing the flexibility and advanced features that expert users need





Test Blocks



Wilson Rockwell Test Blocks

- We work directly with the steel and brass mills to specify the chemical composition.
- Our machining processes (grinding, lapping, polishing) are all done in house, at the site of calibration.





Rockwell Hardness Testing Calibration Kits

Contain three test blocks (low, medium, and high), an indenter, and a case. Each component can also be purchased separately and has its own part number.





Hardness Testing

Wilson Vickers & Knoop Test Blocks

100% inspection to ensure that every single test block meets the physical requirements of ASTM (thickness, flatness, parallelism, surface roughness).

Wilson Brinell Test Blocks

- Uniform material
- Grid pattern supports
 NADCAP compliance
- Large block size



Metallography Supplies & Consumables



Consumables for Material Preparation Testing and Analysis

- Sectioning
- Mounting
- Grinding & Polishing
- Hardness Testing

Full Lab Metallography Solutions

- Grinding and polishing discs
- Precision sectioning blades compatible with most manufacturer's equipment
- Polishing compounds for virtually any application
- Epoxy or Acrylic based mounting compounds
 - 2 –part, heat cured, and compression technologies











Buehler Image Analysis Image Software

- Flexible platform with pre-configured software or hardware packages and optional accessories
- Optional Capture and Measurement Modules available to customize software solution
- Any standard format image may be viewed directly from a calibrated microscope or be imported into OmniMet for analysis

86-1-1001	86-1-1000	OmniMet Viewer allows networked users to database on the same network.
	86-1-1010	OmniMet Capture N' Measure (CnM) enab scale bar (without database functions). Mea perimeter, radius, angle and count. Images the image but cannot be stored or exported
86-1-1003	86-1-1002	OmniMet Basic includes everything in Cap archiving as well as MS Office report templa added for specific applications.
86-1-1005	86-1-1004	OmniMet Advanced includes everything in capabilities. Measurements can be saved in statistical analysis streamlines interpretatio Advanced Measurement Modules may be a
86-1-1007	86-1-1006	OmniMet Express includes everything in O automated Scripts. Scripts are application s and reproducibility for repeat analysis in hig Advanced Measurement Modules and pre-p
86-1-1009	86-1-1008	OmniMet Enterprise includes everything in editing Scripts. Fully customizable Scripts a with 8 commonly used Application Specific Modules and additional Application Specific



Metallography Software

to view and modify images and information in an Omnimet

bles image capture with basic measurement functions and easuring tools include length, parallel lines, curved line, area, s can be saved in common formats. Results can be burnt into ed to Excel®.

pture 'N Measure, and also adds databasing functionality for lates for presenting results. Optional Capture Modules may be

n OmniMet Basic, and also adds enhanced measurements n the database, or interactively to Excel worksheets. Built in on of results and reporting. Optional Capture Modules and added for specific applications.

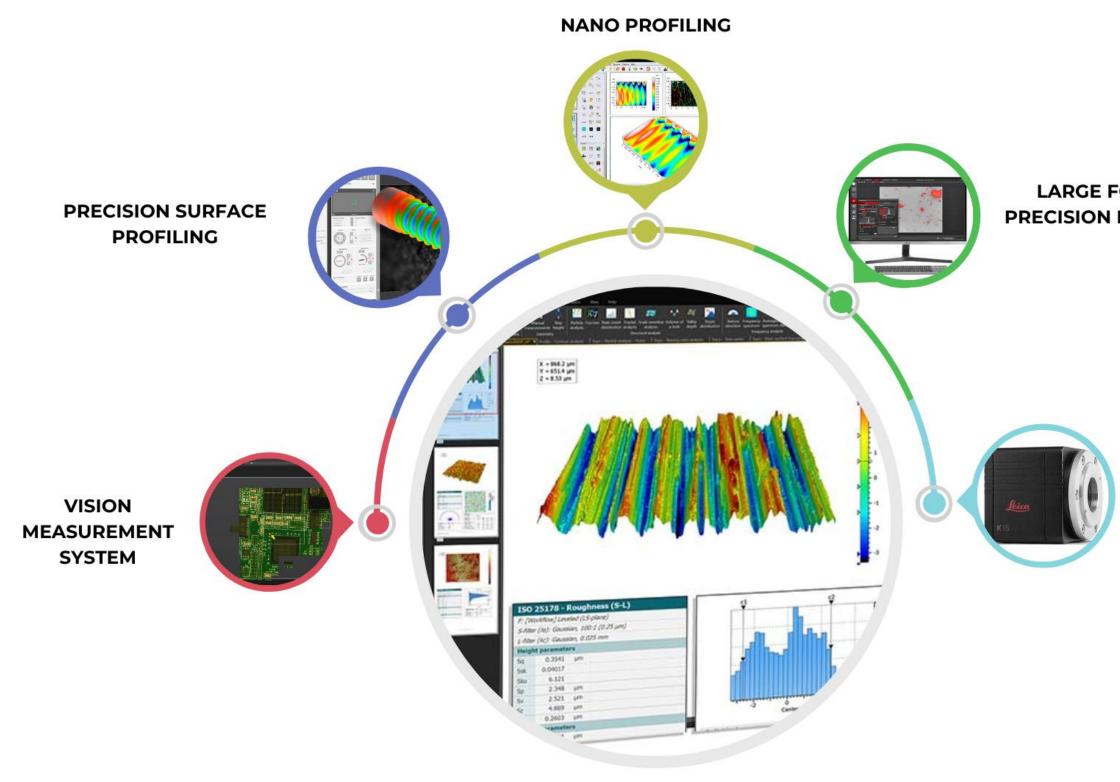
OmniMet Advanced, with the added capability of running specific image analysis packages to provide best efficiency igh throughput environments. Optional Capture Modules, -programmed Application Specific Scripts may be added.

in OmniMet Express, with the added capability of writing and allow the user complete control of analysis solutions. Comes ic Scripts. Optional Capture Modules, Advanced Measurement fic Scripts may be added.











Metrology

LARGE FORMAT **PRECISION PROFILING**

MEASURING MICROSCOPES

Main TOC



Vision Measuring Systems

- Manual
- Semi-Automated
- Automated
- 2D & 3D



QuickScope & Quick Image

- Manual/Semi-Auto
- Errors due to focusing are eliminated
- Simple execution of multiple measurements



Mitutoyo Quick Vision Active Compact CNC Vision combines the flexibility of multiple zoom lenses with touch probe capability to provide a versatile measuring system



Quick Vision Hyper

- Programmable Power Turret (PPT)
- Tracking Auto Focus (TAF)
- Programmable Ring Light (PRL)





Metrology

• Programmable LED stage and coaxial light • 4-quadrant LED ring light • High-resolution and high-speed color camera

Quick Vision Stream Plus

Innovative vision measuring machine that gains images without stopping the stage.





Precision Surface Profiling

Confocal > Interferometry > Focus Variation > Layer Thickness



Sensofar S neox

Configurations available:

- Confocal
- Interferometry
- Focus variation
- Layer Thickness





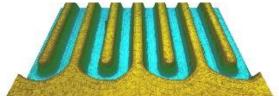
Sensofar S neox Grand Format

A high-performance, non-contact 3D optical profiler designed for advanced surface metrology applications of large panels in semiconductor, display, and PCB industries.

The S neox Grand Format Cleanroom provides three different optical technologies to image with the most suitable technology for each specific sample, achieving precision down to subnanometer levels.



Metrology



Sensofar S lynx 2

Compact precision surface profiling featuring nano-scale accuracy at an affordable cost

Sub TOC





Large Format Precision Profiling



Sensofar S wide

The S wide system uses Fringe Projection technology to quickly acquire large-area measurements with high vertical resolution. It includes analysis tools to extract data on roughness, flatness, critical dimensions, GD&T, and CAD comparisons.



Sensofar S neox Five Axis

Optical profiler combines a high-accuracy rotational module with the advanced inspection and analysis capabilities of the S neox 3D optical profiler. This enables automatic 3D surface measurements at defined positions which can be combined to create a complete 3D volumetric measurement.



Metrology



Measuring Microscopes



Toolmakers Measuring Microscope

Well suited for measuring dimensions and angles of machined metals.



Manual Measuring Microscope



Motorized High-accuracy Measuring Microscope

User-friendliness, high measurement data throughput, and environmental friendliness

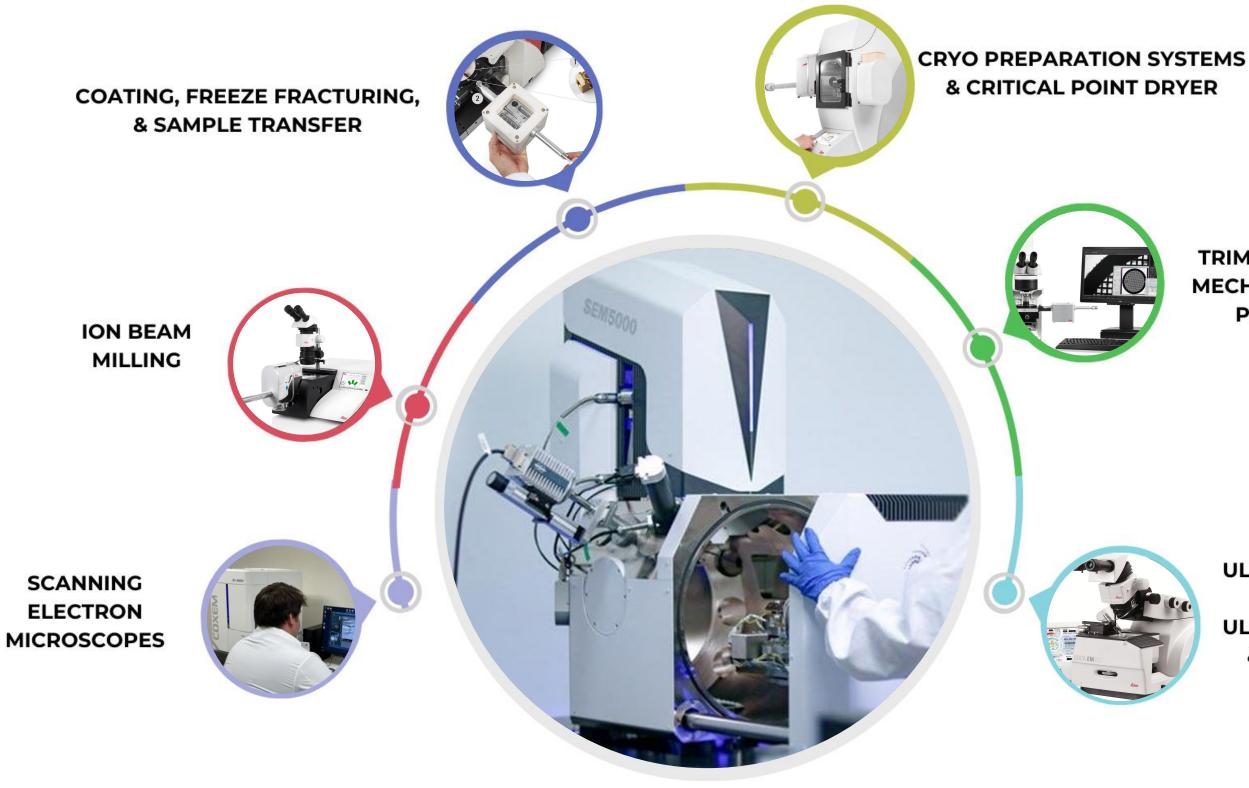


Metrology

• Measure multiple workpieces simultaneously • Simple go/no-go judgment of multiple workpieces

• Generate reports and observe all in one instrument







Electron Microscopy & Sample Prep

TRIMMING & MECHANICAL PREP

> ULTRAMICROTOMES, CRYO ULTRAMICROTOMES, & CONTRASTING



Tabletop & Compact Floor Standing SEM's



EM-30N Table-top SEM

With specifications and capabilities not matched by any other SEM in its price range. After evaluating the EM-30 Series your search will be over to find the best compact SEM available.





EM-40 Table-top SEM

New standards for compact, benchtop, and desktop SEMs by offering you advanced features typically found only in larger, more expensive models.





Electron Microscopy & Sample Prep

CX-200K Compact SEM

The standard supplied configuration of the CX-200plus includes both SE and BSE imaging detectors and an internal chamber view camera for easy stage tilt and height adjustments.

CX-300K Compact SEM

Up to 100mm X,Y travel in a compact size





Full-Size Scanning Electron Microscopes



Focused Ion Beam SEM (FIB-SEM)

The CIQTEK DB550 is an advanced Field Emission Scanning Electron Microscope (FE-SEM) with Focused Ion Beam (FIB) capabilities, offering comprehensive nano-analysis and fabrication in a single workstation.





Full Size Tungsten SEM

The CIQTEK SEM3300 is a next-generation tungsten filament scanning electron microscope that combines inlens electron detectors with electrostatic and electromagnetic compound objective lenses, enabling lowvoltage analysis previously only available in field emission SEMs.



Electron Microscopy & Sample Prep

Full Size Field Emission SEM

The CIQTEK SEM5000X is an ultrahigh resolution Field Emission Scanning Electron Microscope (FESEM) with optimized electron optics that reduce aberrations by 30%, enabling 0.6 nm resolution at 15 kV.







Ion Beam Milling & Trimming Systems

Electron Microscopy & Sample Prep



EM TIC 3X

Allows production of cross sections and planar surfaces for Scanning Electron Microscopy (SEM), Microstructure Analysis (EDS, WDS, Auger, EBSD) and, AFM investigations.





CP-8000+

An advanced sample preparation tool that etches a cross section of a sample using an argon ion beam.





EM TRIM2

High-speed milling system with an integrated stereomicroscope and LED ring illuminator for trimming biological and industrial samples prior to ultramicrotomy.

EM TXP

Target Surfacing System, target preparation device for milling, sawing, grinding, and polishing samples prior to examination by SEM, TEM, and LM techniques.







Coating, Freeze Fracturing, & Sample Transfer

Electron Microscopy & Sample Prep



EM ACE200

Low vacuum sputter and carbon thread coater, producing homogenous and conductive metal or carbon coatings for SEM and TEM analysis was never before more convenient





SPT-20

The SPT-20 Sputter Coater is a compact ion coating system ideal to support table-top SEM's. The system is able to sputter noble metals such as gold (Au), palladium (Pd), platinum (Pt), and silver (Ag) for non-conductive or poorly conductive specimens.



EM ACE600

High vacuum sputter coater processes yield reproducible results you can trust and enable you to increase your sample output with every run.

Sub TOC

Main TOC



Freeze Fracturing, Sample Transfer, & Critical Point Dryer

Electron Microscopy & Sample Prep



EM ACE900 Freeze Fracture System

- Cold shield around the sample • avoids water molecules freezing onto your sample
- Accurate temperature control during the complete process
- Clean Knife fresh blade for • each cut avoids contamination





Leica EM VCT500

- Stay Connected
- Connect your workflow systems
- docked



EM CPD300: Critical Point Dryer

- Automated drying system for biological and industrial samples
- Delivers consistent highquality specimen preservation
- Features safe waste disposal system with no user contact

Optimize your sample transfer thanks to the active sample cooling and new valve concept • Monitor your sample with respect to temperature and vacuum at any time during the workflow when





Ultramicrotomes & Cryo-Ultramicrotomes

Electron Microscopy & Sample Prep



EM UC7

Ultramicrotome provides easy preparation of semi- and ultrathin sections and perfect, smooth surfaces of biological and industrial samples for TEM, SEM, AFM, and LM examination.

EM FC7 Cryochamber

- Full control integration with the EM UC7 touchscreen control panel
- Highly stable temperature regulation and low LN2 (liquid nitrogen) consumption

Three different cryo-modes available for use:

1) standard, 2) high gas flow, and 3) wet cryo-sectioning

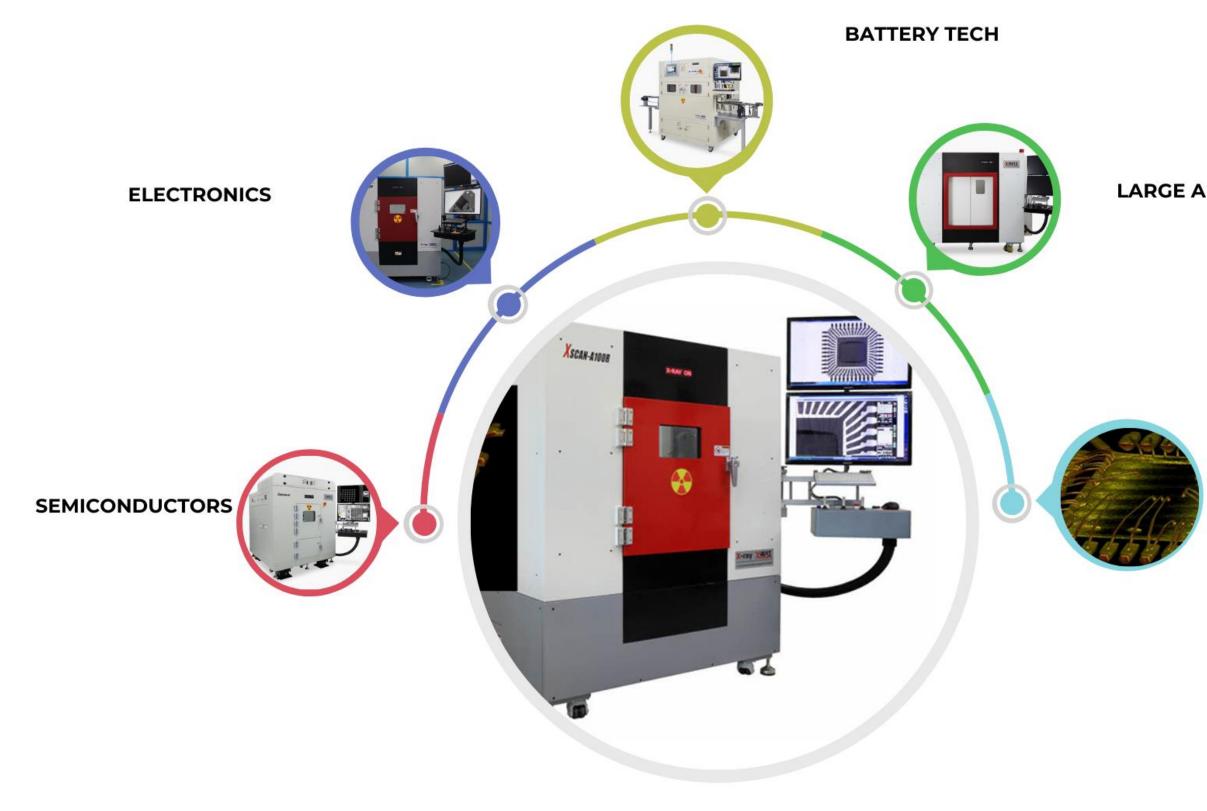




Sub TOC









X-Ray Imaging

LARGE AREA

INSPECTION & ANALYSIS

Main TOC



Inspection & Analysis



X-ray systems for Electronics

The XSCAN-A series consists of four advanced X-ray inspection systems (A100R, A130H, A150, and A100W).





X-ray systems for Semiconductor

The XSCAN-H series offers three high-powered X-ray inspection systems (H130-OCT, H160-OCT, and H160M) featuring hybrid 2D/3D inspection capabilities with automation technology.





X-Ray Imaging

X-Ray systems for Battery Technology

The XSCAN-9000 series offers four specialized X-ray inspection system variants (Prismatic, Cylindrical, Polymer, and Polymer Stack) designed for comprehensive battery and condenser inspection.

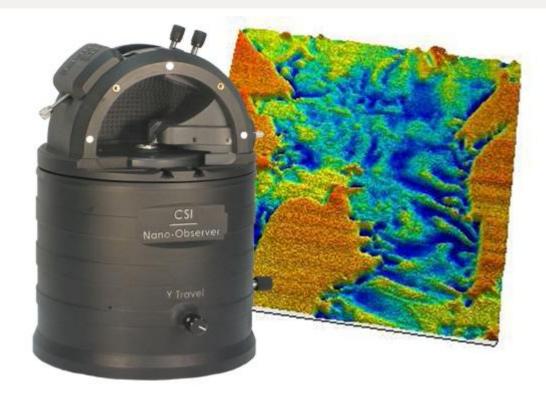
X-Ray systems for large area applications

The XSCAN C series encompasses four highpowered X-ray inspection systems ranging from 150kV to 225kV, designed for large-scale industrial applications.





Nano-Observer



X-ray systems for Electronics

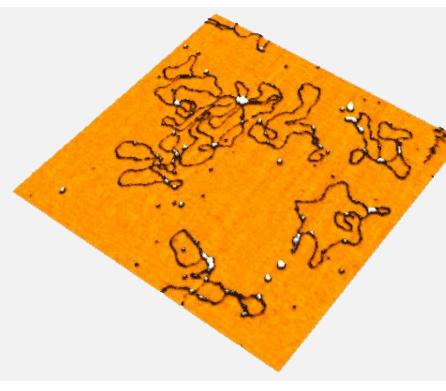
The Nano-Observer AFM microscope is a flexible and powerful AFM. Designed with the ultimate technologies, it combines performance and ease of use.

Compact and robust, the Nano-Observer Atomic Force Microscope fulfills the requirements for advanced users or beginners

- High Resolution AFM •
- Top & side views
- Intuitive software
- Mechanical characterization (Stifness, Adhesion)

Multiple AFM Modes





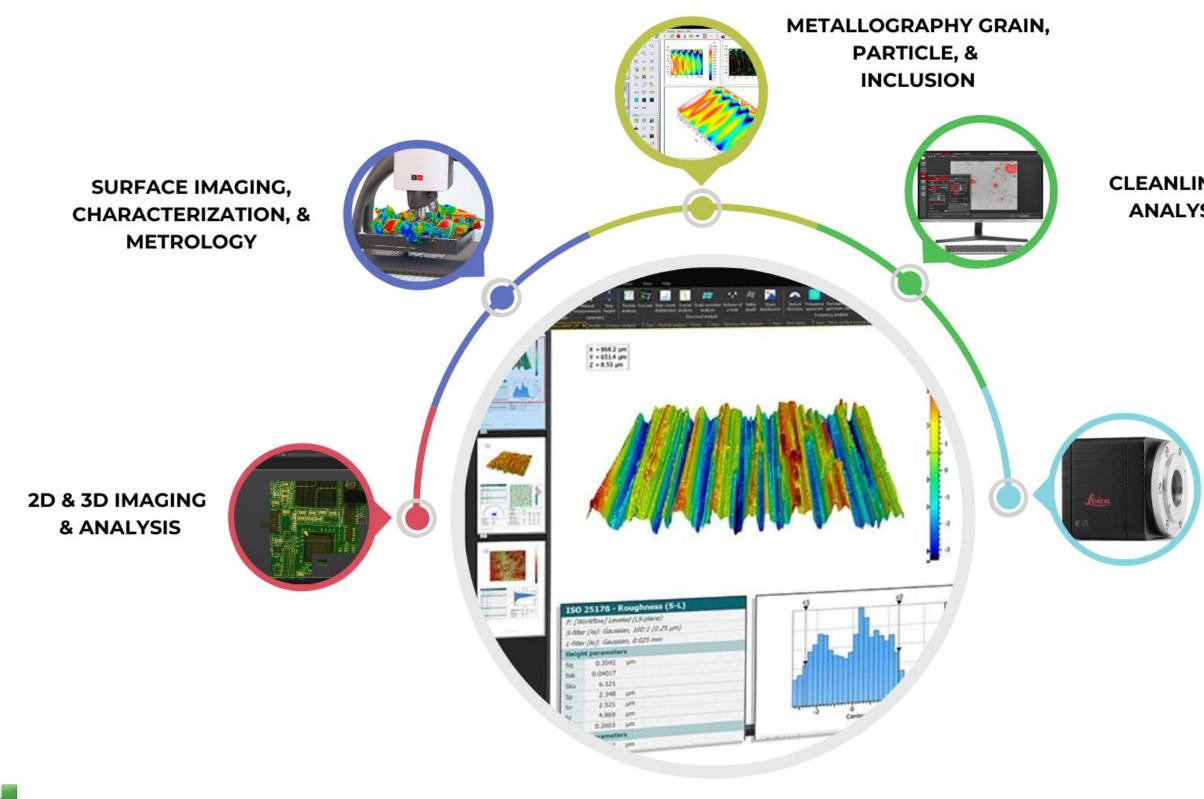


Atomic Force Microscopy



Applications

- Material characterization
- Polymer science
- Electrical characterization
- Semiconductor
- Soft sample
- Biology





Cameras, Lenses, Software & Imaging

CLEANLINESS ANALYSIS

> CAMERAS, LENSES, & ADAPTERS

> > Main TOC



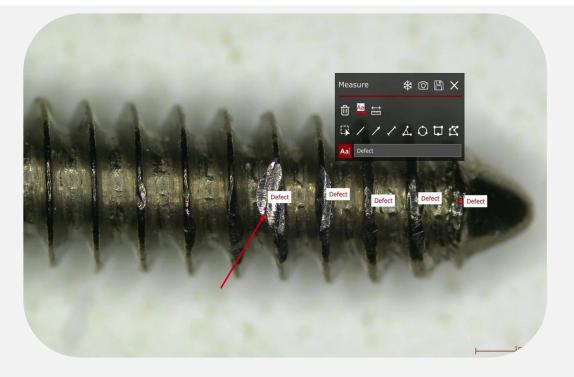
Enersight



Enersight Microscope Software Platform

- Eliminates hassle of navigating different software across workstations
- Streamlines quality control and inspection workflows
- Unified platform for consistent operation





Inspection and Quality Control

- Simplifies and streamlines inspection and documentation workflow ٠
- Provides consistent, easy-to-use interface for all quality processes ٠

Streamline your inspection process

- All-in-one integrated software solution
- Improves inspection efficiency through streamlined tools ٠
- Easily compare, measure, and share data across systems ٠



Cameras, Imaging, & Software

Consistent operation that saves you time

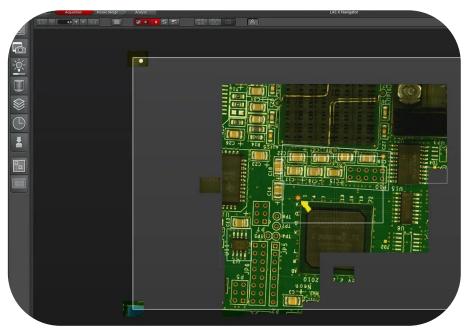
- Common interface works across multiple operation modes
- Features on-screen display • (OSD) functionality
- Reduces learning curve and improves efficiency

Sub TOC

Main TOC



2D & 3D Imaging, Measurement and Analysis

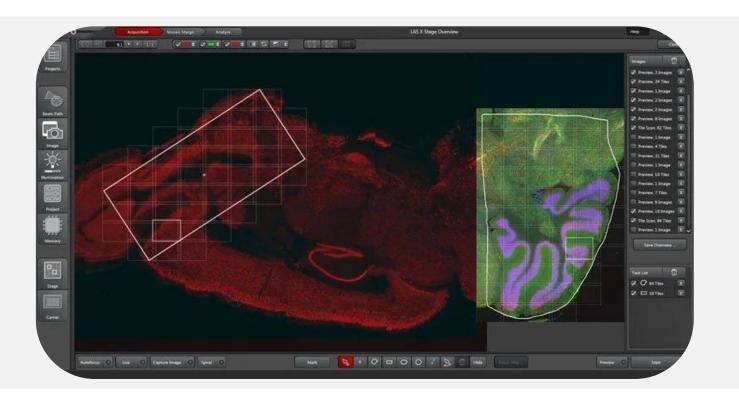


Leica LAS X

- LAS X Live Image Builder •
- LAS X Z-Control & SW ٠ Autofocus
- LAS X Extended Depth of Field
- LAS X Stitching
- LAS X 3D Surface Viewer
- LAS X 3D Surface ٠ Measurements







LAS X Life Science Microscope Software Platform

The one software platform for all Leica microscopes: It integrates confocal, widefield, stereo, super-resolution, and light-sheet instruments from Leica Microsystems.



Cameras, Imaging & Software

Manual Measuring Microscope

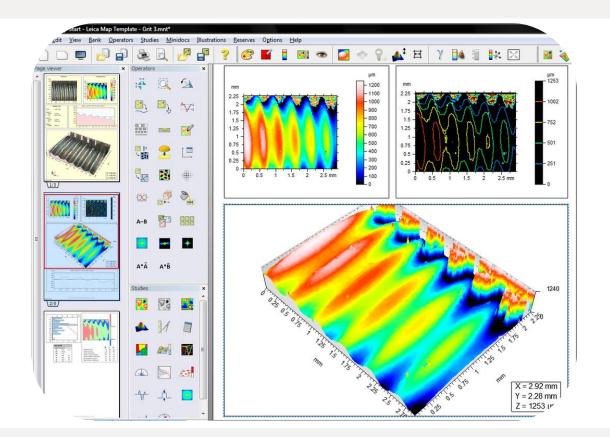
- Measure multiple workpieces
- Simple go/no-go judgement of multiple work pieces
- Generate reports all in one

Sub TOC





Surface Imaging, Characterization, & Metrology

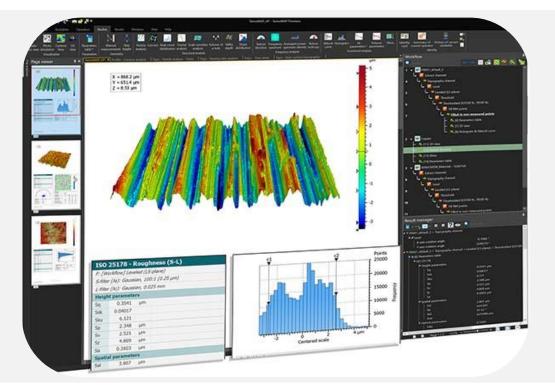


Leica Map is used for viewing and analyzing surface geometry and surface texture from LASX depth map images.

Capabilities include 3D visualization of surfaces, characterization of basic surface features and calculation of surface texture parameters.

SensoMAP Advanced Analysis Software

Based on Mountains technology from Digital Surf, which is an extremely powerful tool for analysis and reporting. Software provides 3D visualizations and characterization of surface features.





Sub TOC

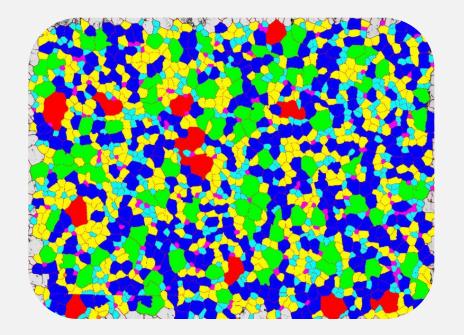




Grain, particle and inclusion

Metallography Imaging & Analysis

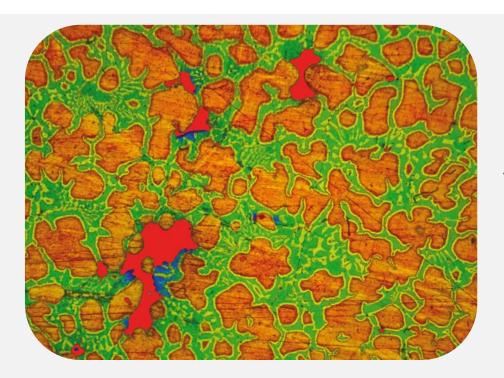
LAS X Modules

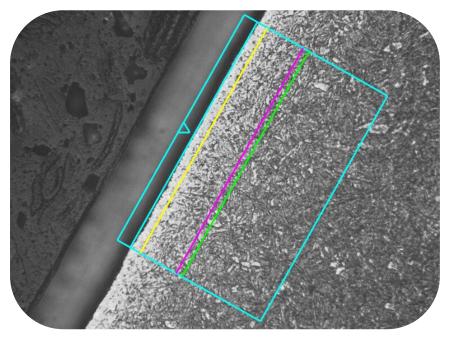


Cast Iron and Grain Expert

Identify graphite nodules and place them in size classes.

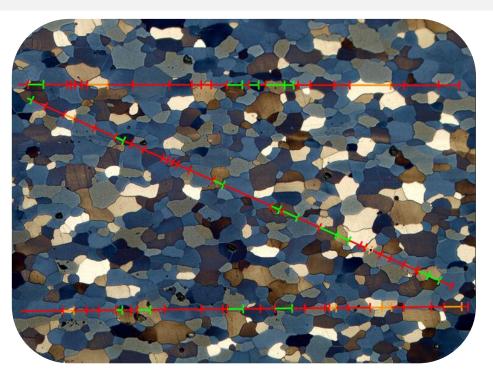
Analyze grain size to evaluate the properties of materials.





Decarburization

identify and analyze the depth of non or low-alloyed steel.





Phase Expert

Measure multi-phase microstructures identified by their distinctive color or contrast in materials.

Metallography Toolbox

Assess, analyze, and measure metals, alloys, layers and coatings, adhering to laboratory requirements by incorporation analysis methods utilized in industry standards.

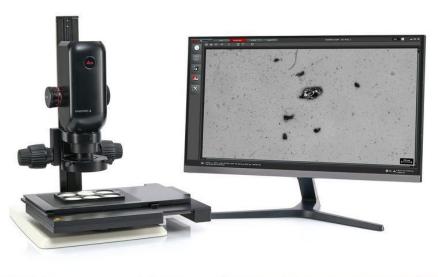


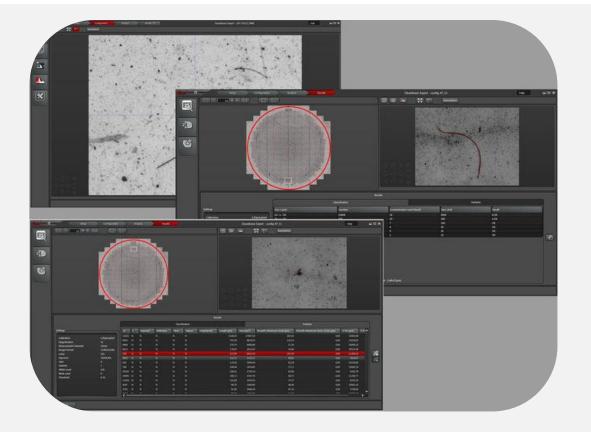




Target contamination fast

Cleanliness analysis systems from Leica Microsystems offer optimized software and a unique 2-in-1 solution for visual and chemical analysis.





Ensure you get your cleanliness analysis results more efficiently:

- Save 30% of your filter sample scanning time for particle sizes between 5 - 10 micrometers.
- For particle sizes over 25 micrometers, you can scan particles on filter • samples 3 x faster.
- Identify the reflective particle on your filter sample faster and • calculate the circular diameter of irregularly shaped particles with improved speed thanks to optimized algorithms.



Cleanliness Analysis

Your benefits

- Increase throughput by analyzing more in less time.
- Obtain more insights on the source of particles for better risk assessment and more confident decisions.
- Meet all your current needs and be prepared for changing requirements.

Sub TOC





Standalone Operation-Enersight

Camera Name	Flexacam C5	Flexacam i5 (stereo)	Flexacam i5 (compound)	КЗС	K3M	K5C
Article Number	1270536	12730536	12730537			
	rievacam (e5					
Application	Education + Routine			High End Single Shot - Documentation and Analysis		
Resolution						
Speed						
Sensitivity						
Interface	USB3	USB3	USB3	USB3	USB3	USB3
Type of Sensor	CMOS	CMOS	CMOS	CMOS	CMOS	CMOS
Surface Diagonal	7.81 mm	7.81 mm	7.81 mm	8.92 mm	8.92 mm	15.86 mm
FPS	60	60	60	15	21 (HW Trigger)	32
Cooling	No	No	No	No	No	No
A/D Converter	12 Bit	12 Bit	12 Bit	12 Bit	12 Bit	12 Bit
Exposure Time	1ms-125 ms	1ms-125 ms	1ms-125 ms	1ms-10s	1ms-10s	1ms-10s
Largest Capture	12 MP	12 MP	12 MP	6 MP	6 MP	20 MP
c-Mount Adapter	0.5x/0.55x	internal,0.5x	internal,0.5x	0.5x/0.55x	0.5x/0.55x	1.0x
Software PC	Enersight Desktop	Enersight Desktop	Enersight Desktop	LASX	LASX	LASX
Software Mac			-	Acquire	Acquire	Acquire
	Flexacam C5	Flexacam i5 (stereo)	Flexacam i5 (compound)	КЗС	КЗМ	K5C



Cameras

Sub TOC



Typically used for in-process inspection, high-speed imaging, imaging in vacuum chambers, or utilizing right angles for hard to image areas.





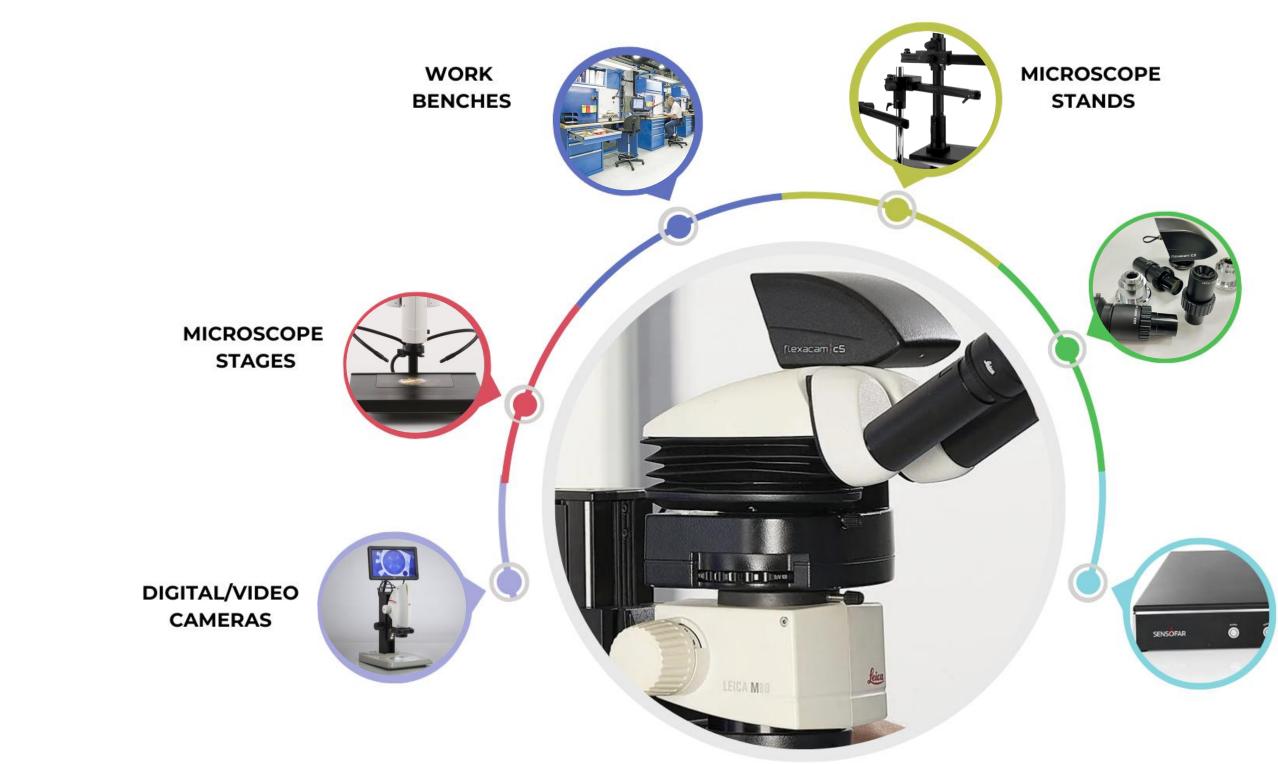
Video Lenses System & Optics

UV/DUV/NUV **IMAGING LENSES**

HIGH SPEED LENSES

Main TOC







Optical Accessories

CAMERA COUPLERS

VIBRATION TABLES







Optical Values

BEWARE OF "EMPTY" MAGNIFICATION

> **MIL TO MICRON** CONVERSION TABLE



1. Human Eye (Unaided)

Maximum resolution: Around 0.4 nm (100 micrometers)

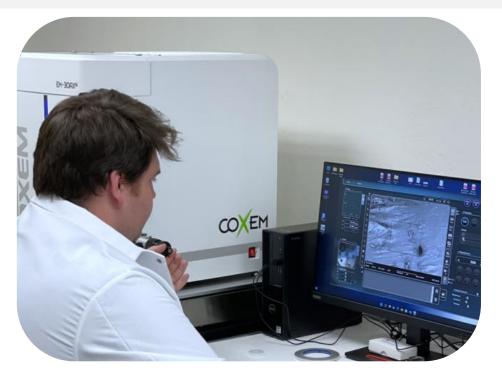




3. Compound Microscope

Also known as an Optical Microscope

Maximum resolution: Around 0.2 micrometers (200 nanometers)





Resolution Capabilities

2. Stereo Microscope

Also known as a Dissecting Microscope

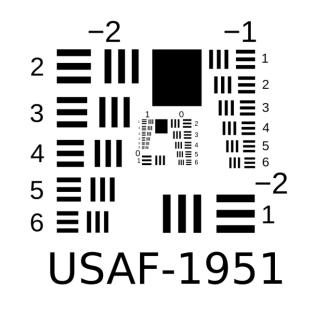
Maximum resolution: Around 1 micrometer (1,000 nanometers)

4. Scanning Electron Microscope (SEM)

Maximum resolution: Around .5 nanometers (0.5 billionths of a meter)







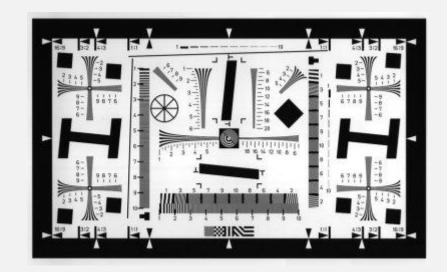
Resolution test charts have been used since the late 19th century to evaluate and calibrate the resolving power of imaging systems such as microscopes, cameras, and optical devices.

The 1951 USAF resolution test chart, defined by MIL-STD-150A, features stepped spatial frequency patterns and is widely used in optical engineering to assess resolution in microscopes, cameras, and scanners.

In the 1960s, the National Bureau of Standards (now NIST) introduced the NBS 1963A Microcopy Resolution Test Chart, designed to assess resolution, contrast, and distortion.

Other charts have been developed for specific uses, including the ISO 12233 Resolution Test Chart for digital cameras and the SEMI P28 Resolution Target for semiconductor inspection.

Today, resolution test charts remain essential tools across microscopy, photography, printing, and imaging industries to ensure consistent, high-quality imaging performance.





Resolution Test Charts & History







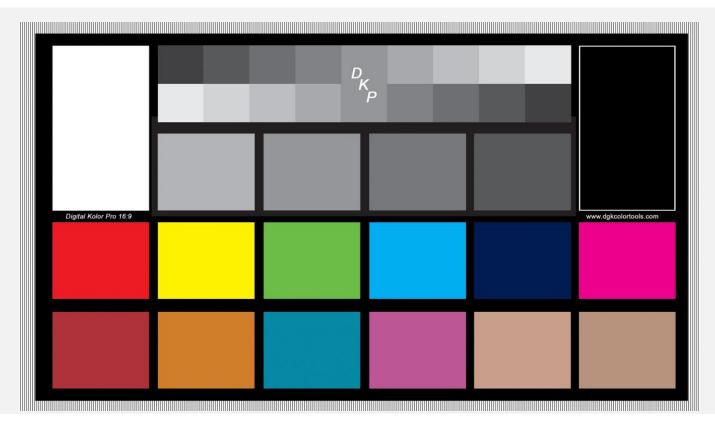
Color Chart & White Balance

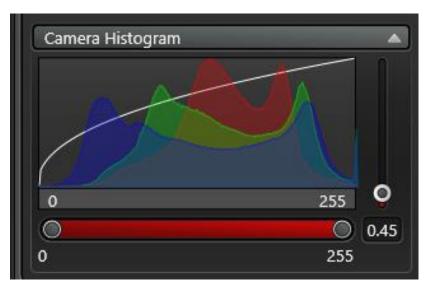
White Balance – What It Is and Why It Matters

A camera setting that defines what "true white" looks like under current lighting. It sets a baseline for all other colors, ensuring accurate, naturallooking images. Since white doesn't always appear white in different lighting, this correction is essential.

What It Does:

- Applies to both photography and videography
- Adjusts all colors based on a defined "white"
- Prevents yellowish or bluish color casts





How It Works:

- especially in mixed lighting.



• Auto White Balance (AWB): Most cameras default to AWB, which guesses what white is. It's convenient but not always accurate—

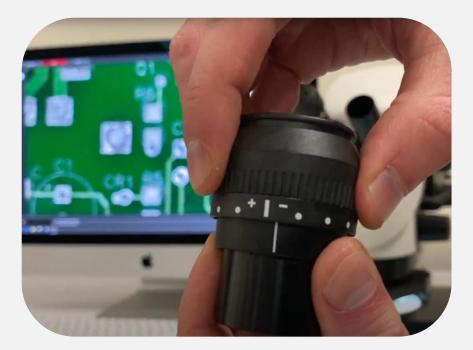
• Manual White Balance: For best results, use a white or grey card to manually set the balance. This tells the camera exactly what "true white" is in your scene, leading to more accurate color reproduction.



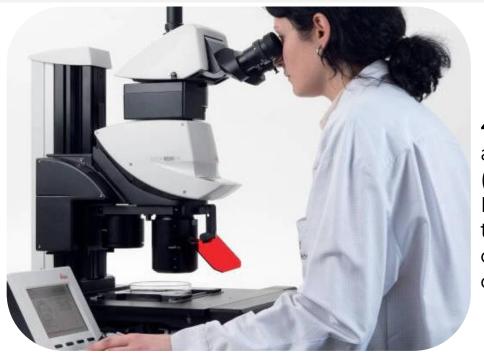


Parfocality Adjustment for All Microscopes

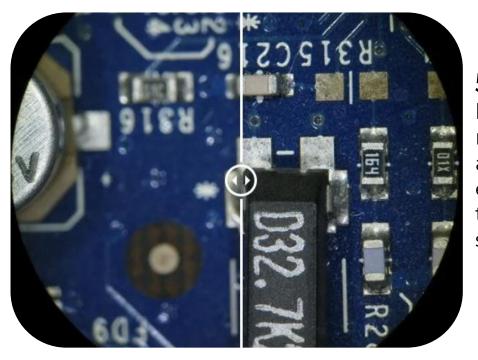
1. Set eyepiece diopter adjustment (lines on the side of eyepiece) to zero or where the two lines meet between the + and signs. If only one eyepiece adjusts, just set that one. Some microscope may have adjustable eye tubes instead of adjustable eyepieces. In that case you will need to adjust the tube where the eyepieces go, not the eyepiece.



microscope.



4. Close your left eye and adjust the right eyepiece (focus) until the image is sharp. Now repeat this process with the left eye. If the microscope only has one adjustment, you only need to adjust one side.





2. Go to the highest magnification on the microscope and focus on a sample. Preferably a thin, flat sample.

3. Now go to the lowest magnification on the

5. Check parfocality by going back to the highest magnification and focusing on a sample. Do not re-adjust eyepieces or tubes. Now go to the lowest magnification. The sample should stay in focus.

Sub TOC





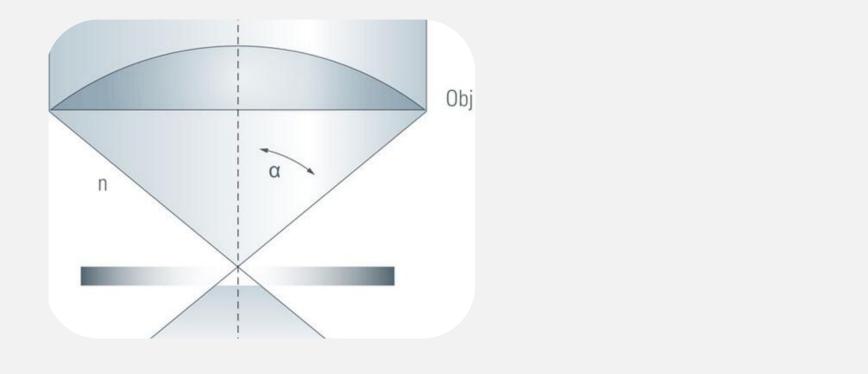
Beware of "Empty" Magnification

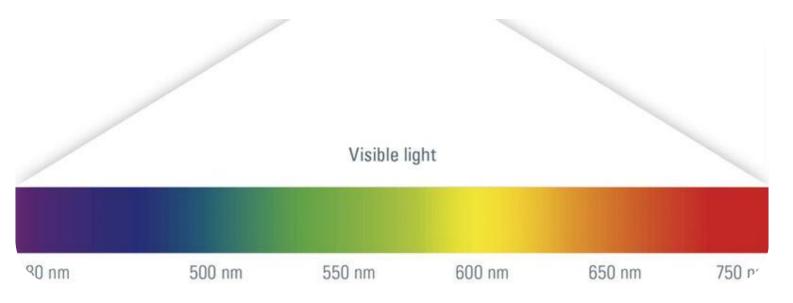
The numerical aperture of the objective determines the detail resolution and brightness of the image.

Light Wavelength Sets the Resolution Limit

Microscope performance depends on resolution, not just magnification. Resolution is the ability to distinguish two closely spaced points. According to the Rayleigh criterion, the minimum resolvable distance is about half the wavelength of light:

- Blue light: d ≈ 0.2 µm
- Red light: d ≈ 0.35 µm
- UV objectives: just under 0.2 µm
- Human eye limit: ~0.2 mm





Resolution also depends on Numerical Aperture (NA), defined as:

NA = n × sin α

- n = refractive index (e.g., nair = 1, noil \approx 1.5)
- α = half the angular aperture of the objective

In air, NA \approx 1. With immersion oil, NA can reach ~1.45, improving resolution.



nair = 1, noil ≈ 1.5) ture of the objective







More Magnification is not Always Better

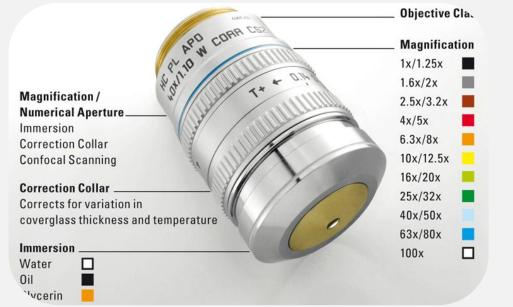
Magnification and Resolution in Optical Microscopy

A basic optical microscope uses two lenses:

- Objective (near specimen)
- Eyepiece (near eye)

Total magnification = objective × eyepiece

Example: 40× objective × 10× eyepiece = 400× magnification



interdependent.

- - - ≈ **0.8**

However, NA has limits. So does **useful** magnification, which falls between: 500 × NA to 1,000 × NA

- Practical magnification limit: ~1,400×
- Anything beyond = "empty magnification" (larger image, no added detail)

Example:

JH TECHNOLOGIES

Hard metal (10% cobalt, 0.6 µm grain size):



(Courtesy of Konrad Friedrichs GmbH & Co KG, Kulmbach, Germany).

Beware of "Empty" Magnification

Resolution must be high enough to make magnification meaningful—they are

Low magnification = low numerical aperture (NA) = low resolution • High magnification = high NA • Example: 40× dry objective typically has NA

```
Left View - Dry objective,
  NA = 0.90
• Right View - Oil
  immersion objective, NA =
  1.30(Oil improves
  resolution due to higher
  NA)
```

Is Magnification of 20,000x Really Useful with Digital Microscopy

Digital vs. Optical Microscopes

- Digital microscopes use a camera only-no eyepieces.
- Stereo and optical microscopes can be fitted with digital cameras for hybrid use.
- Both types serve diverse technical and industrial applications.





Magnification Defined

Magnification = Image feature size / Actual feature size

This gives lateral (2D) magnification.





Digital systems may claim very high magnification (e.g., 20,000×), but true performance depends on resolution and optical quality, not just magnification numbers.

The Best of Both Worlds

Microscopes with both camera and eyepieces offer digital convenience and allow visual color accuracy checks through the eyepieces.







Mil [mil, Thou]	Micron [µ]		
0.01 mil, thou	0.254 µ		
0.1 mil, thou	2.54 µ		
1 mil, thou	25.4 µ		
2 mil, thou	50.8 µ		
3 mil, thou	76.2 µ		
5 mil, thou	127 µ		
10 mil, thou	254 µ		
20 mil, thou	508 µ		
50 mil, thou	1,270 µ		
100 mil, thou	2,540 µ		
1,000 mil, thou	25,400 µ		

How to Convert Mil to Micron

1 mi, thou = 25.4 µ 1 μ = 0.0393700787 mil, thou

Example: convert 15 mil, thou to µ: 15 mil, thou = 15 x 25.4 μ = 381 μ



Visit www.unitconverters.net/length/mil-to-micron.htm to learn more.

Mil to Micron Conversion Table





